




<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10697122</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>CHANG ET AL.</p>
	<p>Examiner</p> <p>Nguyen, Jennifer T</p>	<p>Art Unit</p> <p>2629</p>

Class	SubClass	Date	Examiner
345	102, 207, 211	8/1/06	JN

U.S. Patent and Trademark Office	Part of Paper No.:
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<b>Search Notes</b>  	Application/Control No.  10697122	Applicant(s)/Patent Under Reexamination  CHANG ET AL.
	Examiner Nguyen, Jennifer T	Art Unit 2629

Notes	Date	Examiner
East search, PAJ	8/1/06	JN
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<b>Interference Searched</b>  	Application/Control No.  10697122	Applicant(s)/Patent Under Reexamination  CHANG ET AL.
	Examiner Nguyen, Jennifer T	Art Unit 2629

Class	SubClass	Date	Examiner
349	112-119	8/1/06	JN
359	245,290	8/1/06	JN

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